

FORM PTO-1449 US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Atty. Docket No. <b>85031A/SLP</b> Customer No. 01333		Serial No.	
If AFTER the later date of the first Office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee		Applicant: <b>Nathan D. Cahill</b>			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)		Filing Date <b>Herewith</b>		Group <b>2882</b>	

  

U.S. PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>dem</i>	6,324,243 B1	Nov. 27, 2001	Edic et al	378	4	
<i>dem</i>	5,270,926	Dec. 14, 1993	Tam	378	4	
<i>dem</i>	6,009,142	Dec. 28, 1999	Sauer et al	378	15	
<i>dem</i>	6,130,930	Oct. 10, 2000	Tam	378	4	
<i>dem</i>	6,233,303	May 15, 2001	Tam	378	4	
<i>dem</i>	6,292,525	Sep. 18, 2001	Tam	378	4	

  

FOREIGN PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES   NO
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
<i>dem</i>	"Practical Cone-beam Algorithm", by L.A. Feldkamp, L.C. David, and J.W. Kress, J. Opt. Soc. AM A/Vol. 1, No. 6, June 1994, pp. 612-619					
<i>dem</i>	"Volumetric Description of Objects from Multiple Views", by Worhty N. Martin and J.K. Aggarwal, IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. PAM1-5, No. 2, March 1983, pp. 150-162					
<i>dem</i>	The Visual Hull Concept for Silhouette-Based Imaged Understanding, by Aldo Laurentini, IEEE Transaction on Pattern Analysis and Machine Intelligence, Vol. 16, No. 2, February 1994, pp 150-162					
<i>dem</i>	"Imaging Processing Techniques for Tumor Detection", robin N. Strickland, ed Marcel Deckker, Inc. NY 2002					
<i>dem</i>	"Computer-Aided Diagnosis in Check Radiography" PhD Thesis, University Medical Center Utrecht, 2001, B. van Ginnekin					
EXAMINER <i>David Brown</i>				DATE CONSIDERED <i>9/14/04</i>		

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.